PCN Number:			20130520005					PCN Dat	e:	06/19/2013		
				ndii	ng packa			embly site for a e from punched				
<b>Customer Contact:</b>		PCN	Ma	<u>anager</u>	ager Phone: +1(214)480-6037		Dept:	Qua	lity Services			
Proposed 1 <sup>st</sup> Ship Da			te:		09/19/2013 Estimated Sample A		Availabilit	y:	07/15/2013			
Change Type:												
Assembly Site			$\boxtimes$	Assembly Process			Assembly Materials					
Design				Electrical Specification			ecification					
Test Site			$\boxtimes$	Packing/Shipping/Labeling			Test Process					
Wafer Bump Site					Wafer Bump Material			Wafer Bump Process				
Wafer Fab Site					Wafer Fab Materials Wafer Fab Process			cess				
PCN Details												

#### **Description of Change:**

Texas Instruments is pleased to announce the ongoing qualification of its CLARK-AT facility as a new assembly site for 4x4 mm, 20-pin RTK VQFN packaged device(s) currently being assembled at its SCSAT subcon facility. A package change (see package mechanical drawings) and an order number change will accompany this change. The sawn RGP package is considered backwards compatible with the punched RTK package, i.e. no PCB footprint change is necessary. Please see the tables below for further details on site and associated RoHS compliant and REACH compliant bill of material changes. Packing materials (shipping boxes, tape & reels, tubes, etc.) at the additional site will be consistent with materials currently in use at that added site.

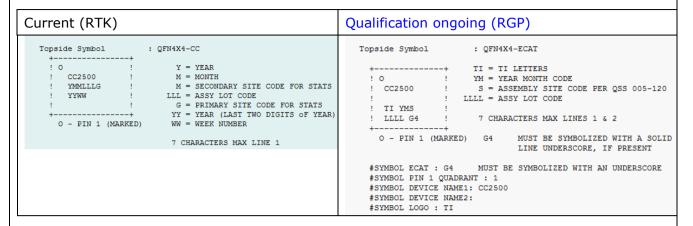
	Current	Qualification
Assembly Site	SCSAT	CLARK-AT
Package Designator	RTK	RGP
Leadframe	SID#R002-2077X (NiPdAu)	4211288-0003 (NiPdAu)
Mount Compound	SID#R008-0103X	4207123-0002
Mold Compound	SID#R003-0302X	4208625-0005
Bond Wire	SID#R005-0077X 25.4 μm (1 mil Au)	4072459-0500 (0.96 mil
		Au)

## **Device Names / Orderables**

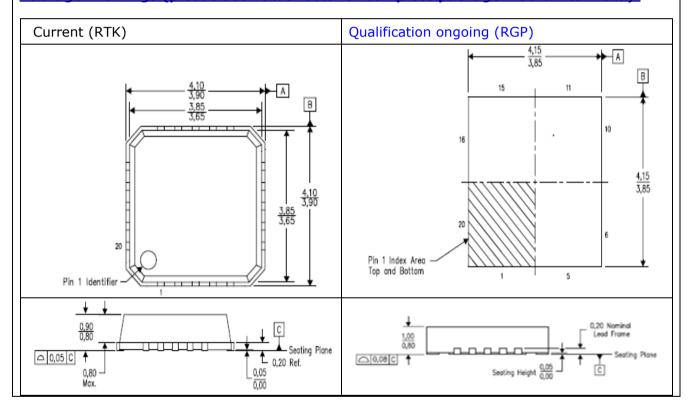
The orderable part number will change to reflect the RGP package. Customers must convert their systems over to the new part numbers when this PCN goes into effect. The "Package Option Addendum" section in the updated datasheet as well as product information page on web will reflect these orderable device changes when they go into effect.

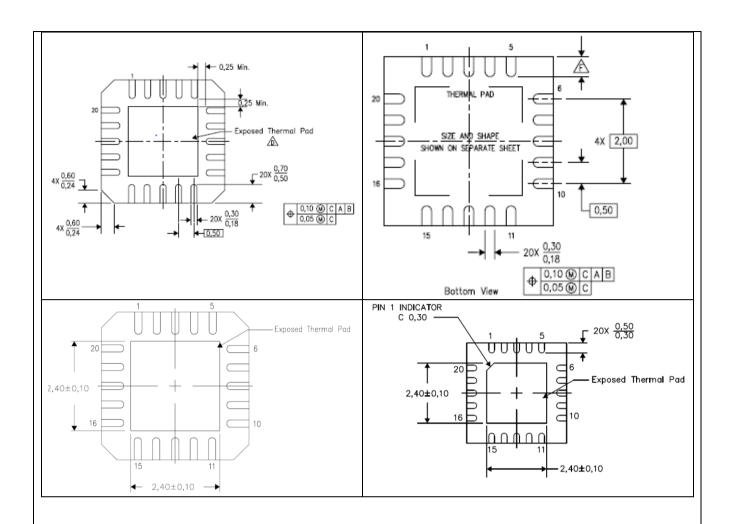
#### Package marking:

CC1101 is used as an example below. The same marking change applies to all affected product.



## Package Drawings (please see datasheets for complete package Mechanical Data):





## **Reason for Change:**

Continuity of Supply

# Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

Improved reliability by changing to sawn RGP package with higher package integrity.

# Changes to product identification resulting from this PCN:

### **Shipment Labels:**

#### Current

Assembly Site	Assembly site Origin (22L)	Assembly country Origin (23L)		
SCSAT	STS	SGP		
New				
Assembly Site	Assembly site Origin (22L)	Assembly country Origin (23L)		
CLARK-AT	QAB	PHL		

Sample product shipping label

TEXAS STRUMENTS MADE IN: Malaysia

MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04

ITEM:

(1P) SN74LS07NSR 31T)LOT: 3959047MLA 4W) TKY(1T) 7523483\$12

(2P) REV: (V) 0033317 (21L) CCO:USA 0033317 20L) CSO: SHE (22L) ASO: MLA (23L) ACO: MYS

### **Product Affected:**

<b>Current Part</b>	
Number	New Part Number
CC2500-RTR1	CC2500RGPR
CC2500-RTY1	CC2500RGP
CC2500RTK	CC2500RGP
CC2500RTKG3	CC2500RGP
CC2500RTKR	CC2500RGPR
CC2500RTKRG3	CC2500RGPR
HPA00325RTKR	HPA00325RGPR
HPA00367RTKR	HPA00367RGPR
HPA00711KBM	HPA00711KBM

# **Qualification Data:**

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

**Qualification Schedule:** Start: 2012-10-15 End: 2013-02-01

Qualification Device Construction Details:						
Device:	See the Product Affected section of this document for a list of qualified devices	<i>Qual Device1 for QBS</i> CC1101RTK	<i>Qual Devic2 for QBS</i> CC1101RGP			
Wafer Fab:	TSMC Fab4	TSMC Fab4	TSMC Fab4			
Wafer Technology:	0.18um CMOS	0.18um CMOS	0.18um CMOS			
Assembly Site:	CLARK-AT	SCSAT	CLAR-AT			
Package Type/Code:	20VQFN / RGP	20VQFN / RTK	20VQFN / RGP			
Package Pins:	20	20	20			
Mold Compound:	4208625-0005	SID#R003-0302X	4208625-0005			
Mold Compound Supplier:	Sumitomo	Sumitomo	Sumitomo			
Lead Frame:	4211288-0003	SID#R002-2077X	4211288-0003			
Composition:	NiPdAu, Cu base	NiPdAu, Cu base	NiPdAu, Cu base			
Die Attach:	4207123-0002	SID#R008-0103X	4207123-0002			
Die Attach Supplier:	Sumitomo	Ablestik	Sumitomo			
Wire Diameter:	24.3 um (0.96 mils)	25.4 um (1.0 mils)	24.3 um (0.96 mils)			
Moisture Level:	MSL3	MSL3	MSL3			

Qualification:  Plan	☐ Test Results			
Reliability Test	Conditions	Sample Size (PASS/FAIL)		
ESD HBM	Human Body Model JEDEC STD 22 A114	3 / 0 3 / 0 3 / 0 3 / 0 PASS (QBS with QD1)		
ESD CDM	Charged Device Model JEDEC STD 22 C101	3 / 0 3 / 0 3 / 0 3 / 0 PASS (QBS with QD2)		
Latch-up	100mA / 1.5xVddmax JEDEC STD 78	18 / 0 PASS (QBS with QD1)		
Manufacturability	Per assembly site specification	-		
Pre-conditioning Level 3	24h bake @ 125°C, 192h soak @ 30°C/60%RH, 3 IR cycles 260°C + 5/-0°C SAM required JEDEC STD 22 A113	693 / 0 PASS (QBS with QD2)		
Temperature Cycles air/air*	-55°C / +125°C JEDEC STD 22 A104	231 / 0 231 / 0 PASS (QBS with QD2)		
Storage*	150°C / 600h JEDEC STD 22 A103	231 / 0 231 / 0 PASS (QBS with QD2)		
Bias Temperature & Humidity*	130°C / 85%RH, Vmax JEDEC STD 22 A101/A110	77 / 0 PASS (QBS with QD1)		
Unbiased HAST*	110°C / 85%RH, Vmax JEDEC STD 22 A118	231 / 0 231 / 0 PASS (QBS with QD2)		
Operating Life Test	Dynamic 140°C (480 Hrs), Vcc Max JEDEC STD 22 A108	77 / 0 PASS (QBS with QD1)		
Thermal Integrity Sequence	(level 3 @ 260C +5/-0C)	12 / 0 12 / 0 PASS (QBS with QD2)		
Electrical characterization	Low (minimum) and high (maximum) extremes for device bias voltage and temperature.	Pass		
Notes:  * Test requires Moisture Preconditioning Qualification tests "pass" on zero fails for each test "QBS" stands for Qualification by Similarity				

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com